

N-Channel 200 V (D-S) MOSFET

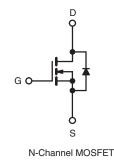
PRODUCT SUMMARY					
V _{DS} (V)	200				
$R_{DS(on)}\left(\Omega\right)$	V _{GS} = 10 V	0.265			
Q _g (Max.) (nC)	16				
Q _{gs} (nC)	5				
Q _{gd} (nC)	8				
Configuration	Single				

FEATURES

- · Isolated Package
- High Voltage Isolation = 2.5 kV_{RMS} (t = 60 s; f = 60 Hz)
- Sink to Lead Creepage Distance = 4.8 mm
- 175 °C Operating Temperature
- · Dynamic dV/dt Rating
- Low Thermal Resistance
- · Lead (Pb)-free Available







ABSOLUTE MAXIMUM RATINGS T	_C = 25 °C, unless otherv	vise noted			
PARAMETER	SYMBOL	LIMIT	UNIT		
Drain-Source Voltage		V _{DS}	200	v	
Gate-Source Voltage		V _{GS}	± 20		
Continuous Drain Current	V_{GS} at 10 V $T_C = 25 \degree C$		10		
	V_{GS} at 10 V $T_C = 100 ^{\circ}C$		6.5	A	
Pulsed Drain Currenta	I _{DM}	32	1		
Linear Derating Factor		0.24	W/°C		
Single Pulse Avalanche Energy ^b		E _{AS}	36	mJ	
Repetitive Avalanche Current ^a	I _{AR}	7.2	A		
Repetitive Avalanche Energy ^a	E _{AR}	3.7	mJ		
Maximum Power Dissipation	T _C = 25 °C	PD	P _D 37		
Peak Diode Recovery dV/dtc	dV/dt	5.5	V/ns		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to + 175	°C	
Soldering Recommendations (Peak Temperature)	for 10 s		300 ^d		
Mounting Torque	6-32 or M3 screw		10	lbf ⋅ in	
	0-52 OF MIS SCIEW		1.1	N ⋅ m	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. $V_{DD} = 25 \text{ V}$, starting $T_J = 25 \text{ °C}$, L = 1.0 mH, $R_G = 25 \Omega$, $I_{AS} = 7.2 \text{ A}$ (see fig. 12). c. $I_{SD} \le 9.2 \text{ A}$, dl/dt $\le 110 \text{ A/}\mu\text{s}$, $V_{DD} \le V_{DS}$, $T_J \le 175 \text{ °C}$.

d. 1.6 mm from case.



PARAMETER	SYMBOL	ТҮР	P	MAX.			UNIT		
Maximum Junction-to-Ambient	R _{thJA}	- 65							
Maximum Junction-to-Case (Drain)	R _{thJC}	- 4.1				°C/W			
SPECIFICATIONS $T_J = 25 \degree C$,	unless other	wise noted							
PARAMETER	SYMBOL	TEST CONDITIONS			MIN.	TYP.	MAX.	UNI	
Static						1	1	1	
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} -	= 0 V, I _D = 250	μA	200	-	-	V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference	ce to 25 °C, I _D	= 1 mA	-	0.13	-	V/°C	
Gate-Source Threshold Voltage	V _{GS(th)}		= V _{GS} , I _D = 250		2.0	-	4.0	v	
Gate-Source Leakage	I _{GSS}		$V_{GS} = \pm 20 \text{ V}$			-	± 100	nA	
	V _{DS} = 200 V, V _{GS} = 0 V	0 V	-	-	25	+			
Zero Gate Voltage Drain Current		V _{DS} =160 V	, V _{GS} = 0 V, T	ı = 150 °C	-	-	250	μΑ	
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 4	4.3 A ^b	-	0.265	-	Ω	
Forward Transconductance	g _{fs}	V _{DS} =	= 50 V, I _D = 4.3	3 A ^b	2.3	-	-	S	
Dynamic		1							
Input Capacitance	Ciss	$V_{cc} = 0 V_{cc}$			-	560	-	pF	
Output Capacitance	C _{oss}	V _{GS} = 0 V, V _{DS} = 25 V, f = 1.0 MHz, see fig. 5		-	260	-			
Reverse Transfer Capacitance	C _{rss}			-	110	-			
Drain to Sink Capacitance	С		f = 1.0 MHz		-	12	-	1	
Total Gate Charge	Qg				-	-	16	1	
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V	$V_{GS} = 10 \text{ V} \qquad \begin{array}{c} I_{D} = 9.2 \text{ A}, V_{DS} = 80 \text{ V}, \\ \text{see fig. 6 and } 13^{b} \end{array}$		-	-	4.4	nC	
Gate-Drain Charge	Q _{gd}				-	-	7.7		
Turn-On Delay Time	t _{d(on)}	$\label{eq:V_DD} \begin{array}{l} V_{DD} \ = \ 100 \ \text{V}, \ \text{I}_{D} = \ 9.2 \ \text{A}, \\ R_{G} \ = \ 18 \ \Omega, \ \text{R}_{D} = \ 5.2 \ \Omega, \\ \text{see fig. 10}^{\text{b}} \end{array}$		-	8.8	-	1		
Rise Time	t _r				-	30	-	1	
Turn-Off Delay Time	t _{d(off)}			-	19	-	ns		
Fall Time	t _f			-	20	-			
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-			
Internal Source Inductance	Ls			-	7.5	-	- nH		
Drain-Source Body Diode Characteristic	s				•	•			
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	10	-	- A		
Pulsed Diode Forward Current ^a	I _{SM}			-	32	-			
Body Diode Voltage	V_{SD}	$T_{J} = 25 \ ^{\circ}C, \ I_{S} = 7.2 \ A, \ V_{GS} = 0 \ V^{b}$		-	-	2.5	V		
Body Diode Reverse Recovery Time	t _{rr}	$T_J = 25 \ ^{\circ}C, I_F = 9.2 \text{ A}, dI/dt = 100 \text{ A}/\mu \text{s}^{b}$		-	130	260	ns		
Body Diode Reverse Recovery Charge	Q _{rr}			-	0.65	1.3	μC		
Forward Turn-On Time	t _{on}	Intrinsic tu	urn-on time is r	negligible (turn	-on is dor	ninated by	y L _S and I	_D)	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width \leq 300 µs; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

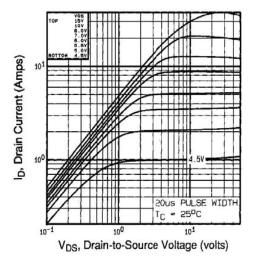


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

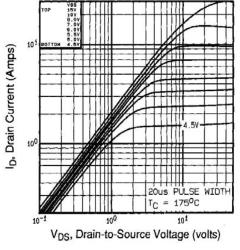


Fig. 2 - Typical Output Characteristics, T_C = 175 °C

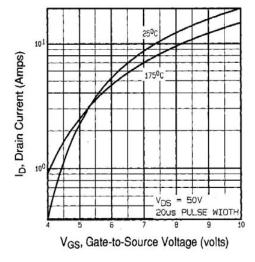


Fig. 3 - Typical Transfer Characteristics

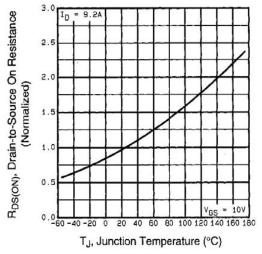


Fig. 4 - Normalized On-Resistance vs. Temperature



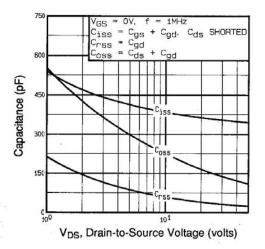


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

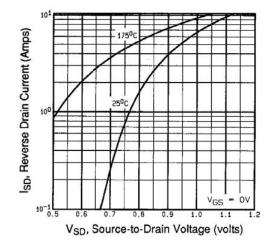


Fig. 7 - Typical Source-Drain Diode Forward Voltage

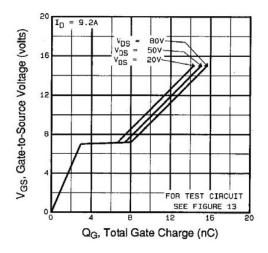


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

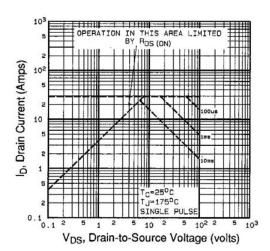


Fig. 5 - Fig. 8 - Maximum Safe Operating Area



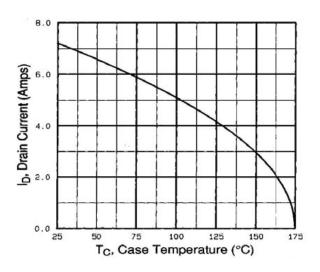


Fig. 9 - Maximum Drain Current vs. Case Temperature

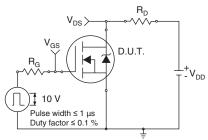


Fig. 10a - Switching Time Test Circuit

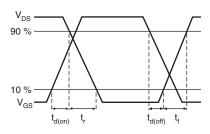
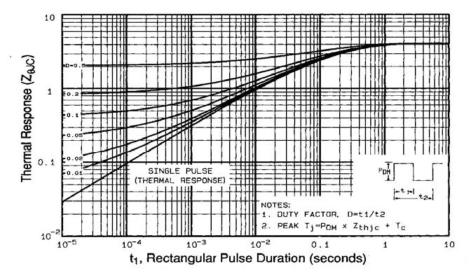


Fig. 10b - Switching Time Waveforms





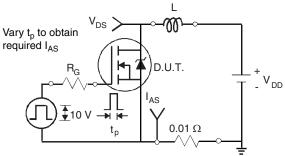


Fig. 12a - Unclamped Inductive Test Circuit

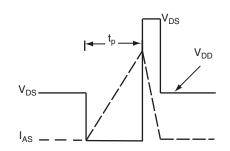
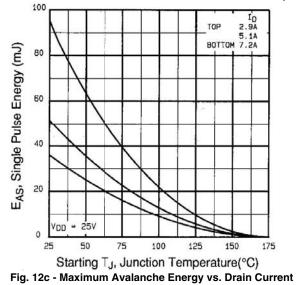


Fig. 12b - Unclamped Inductive Waveforms





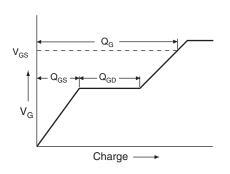


Fig. 13a - Basic Gate Charge Waveform

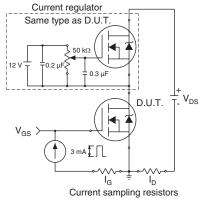
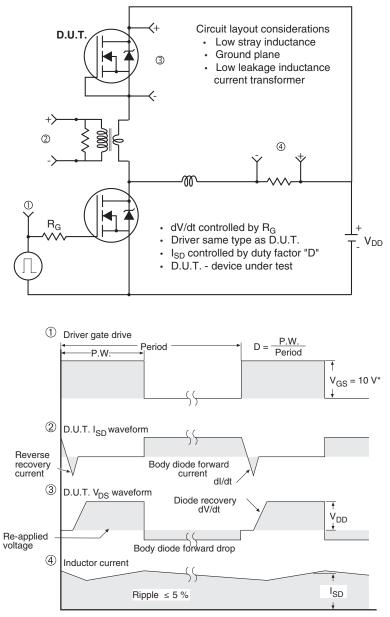


Fig. 13b - Gate Charge Test Circuit





Peak Diode Recovery dV/dt Test Circuit

* $V_{GS} = 5$ V for logic level devices

Fig. 14 - For N-Channel



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